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U.S. Department of Commerce Patent and Trademark Office		APPLICANT HATANO et al.	
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**U. S. Patent Documents**

Examiner Initial		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE

**Foreign Patent Documents**

Examiner Initial	DOCUMENT NUMBER	FILING DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO
S.M.	2002-43222	2/21/95	Japan			Abstract	X
S.M.	2002-100637	2/21/95	Japan			Abstract	X

**Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)**

S.M.	C.T. Angelis, C.A. Dimitriadis, M. Miyasaka, F.V. Farmakis, G. Kamarinos, J. Brini and J. Stoemenos, "Effect of Excimer Laser Annealing on the Structural and Electrical Properties of Polycrystalline Silicon Thin-Film Transistors", Journal of Applied Physics (15 October 1999), Vol. 86, No. 8, pp. 4600-4606
S.M.	Hiroyuki Kuriyama, Tomoyuki, Nohda, Satoshi Ishida, Takashi Kuwahara, Shigeru Noguchi, Seiichi Kiyama, Shinya Tsuda and Shoichi Nakano, "Lateral Grain Growth of Poly-Si Films with a Specific Orientation by an Excimer Laser Annealing Method", Jpn. J. Appl. Phys., Vol. 32 (1993), pp. 6190-6195
S.M.	Kenkichi Suzuki, Masakazu Saito, Michiko Takahashi, Nobuaki Hayashi and Takao Terabayashi, "Correlation Between Power Density Fluctuation and Grain Size Distribution of Laser Annealed Poly-Crystalline Silicon", Part of the SPIE Conference on Laser Applications in Microelectronics and Optoelectronic Manufacturing IV, January 1999, SPIE Vol. 3618, pp. 310-319

EXAMINER

/Seokyun Moon/

DATE CONSIDERED

06/12/2006

*EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant*